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Ì		INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Filing Date	August 9, 2002	
	SIA				First Named Inventor	HISASHI OHTANI et al.	
I					Group Art Unit	2826 2818	
					Examiner Name	Tan Trem D. LE	
I	Sheet	ı	of	3	Attorney Docket Number	0756-7198	

Examiner	Cite	U.S. Patent Document		Name of Detector or Applicant - FOIL-4	Date of Publication of Cited Document	Pages, Columns, Lines, Where Releve Passages or Relevant Figures Apper
laitiels'	No.1		Kind Code <sup>3</sup> (If known)	Name of Patentee or Applicant of Citod Document	MM-DD-YYYY	t sough is property i dries where
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l Examiner	/\/.	Date	Man ALL
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Signature	<u> </u>	Considered	

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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Application Number	<u>Based on S.N. 10/314,693</u> 10	
Filing Date	August 9, 2002 9 108/200	]3
First Named Inventor	HISASHI OHTANI et al.	]
Group Art Unit	<del>2826</del> 2878	]
Examiner Name	Tan Tran D. LE	]
Attorney Docket Number	0756-7198	
	Application Number Filing Date First Named Inventor Group Art Unit Examiner Name	Filing Date   August 9, 2002 9 108 / 2006     First Named Inventor   HISASHI OHTANI et al.     Group Art Unit   -2826   2878     Examiner Name   Tan Tran   D.   LE

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Examiner Signature	L	Date Considered	Mar-04
Signature		Considered	

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INFORMATION DISCLOS	TIDE Application Number	Based on S.N. 19/214,693 10/6		
	71V D-4-	August 9, 2002 9-8-2003		
STATEMENT BY APPLIC	AIN I First Named Inventor	HISASHI OHTANI et al.		
(use as many sheets as necessary)	Group Art Unit	2826- 28/8		
	Examiner Name	Tan Tran D, LE		
Sheet 3 3	Attorney Docket Number	0756-7198		

			U.S. PATENT DOCUMEN	TS	
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Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the stricle (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>				
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